



## **EMCM4 test results**

Belle II PXD EVO meeting

Paola Avella, Daniel Klose, Christian Koffmane for the MPP/HLL team









- Wafer layout
- Test results
- EMCM4 yield
- Fault description
- Conclusions











W	DUT1	DUT2	DUT3	DUT4	DUT5	DUT6	DUT7
24	0	1*	0	0	2	0	0
25	<b>1</b> ,1 <sup>†</sup>	0	1†	0	0	0	0
26	0	0	0	0	0	0	0
27	0	0	0	0	1	0	0
28	0	3†	0	0	0	0	0

• \* High-Ohmic shorts that do not affect the functioning of the module.

- + Low-ohmic short that does not affect the functioning of the module.
- In **red**, lethal shorts.







W	DUT1	DUT2	DUT3	DUT4	DUT5	DUT6	DUT7
24	0	0	0	0	4	0	0
25	4	0	2	0	0	0	0
26	0	0	0	0	0	0	0
27	0	0	0	0	4	0	0
28	0	2	0	0	0	0	0

**Yield = 91.4%** 

W24 – DUT5 (grade 4)  $A_p \cdot \Delta_q \ge \pm t$ 





 W25 – DUT1 (grade 4) Δp. Δg≥±t





Short between TMS and GateON.

 $M_{\Delta_{f},\Delta_{f} \geq \pm t}$  W27 – DUT5 (grade 4)



4	<b>1/5</b>							
	1./6				*****			

Shorts among drain lines and source pads.







Lateral shorts in Al2 drain lines (converted to a comb structure for test purposes).

W28 – DUT2 (grade 2)  $A_p \cdot \Delta_g \ge \pm t$ 





21st October 2014





- Three lethal shorts found in power nets out of 35 modules (DUT5/24, DUT1/25, DUT5/27).
- DUT3/W25 and DUT2/W28 (in general, grade 2 faults) could be repaired.
- The technology of choice for the PXD9 production proves to be stable and reliable, with a high yield (91.4%).
- All PXD9 wafers will be tested after Al1 as well as after Al2 → possibility of rework on the same metal layer.

Thank you for your attention!